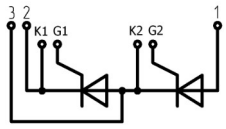
Electrically isolated base plate
Industrial standard package
Simplified mechanical design, rapid assembly
Pressure contact

Double Thyristor Module For Phase Control MTx-400-44-D

Mean on-state current		I_{TAV}	400 A	
Repetitive peak off-state voltage		V_{DRM}	3800...4400 V	
Repetitive peak reverse voltage		V_{RRM}		
Turn-off time		t_q	500 µs	
V_{DRM}, V_{RRM}, V	3800	4000	4200	4400
Voltage code	38	40	42	44
T_j, °C	–40...+125			

MT3



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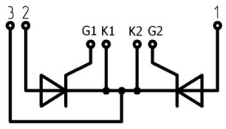

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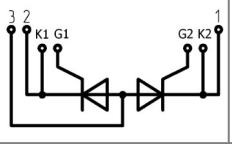
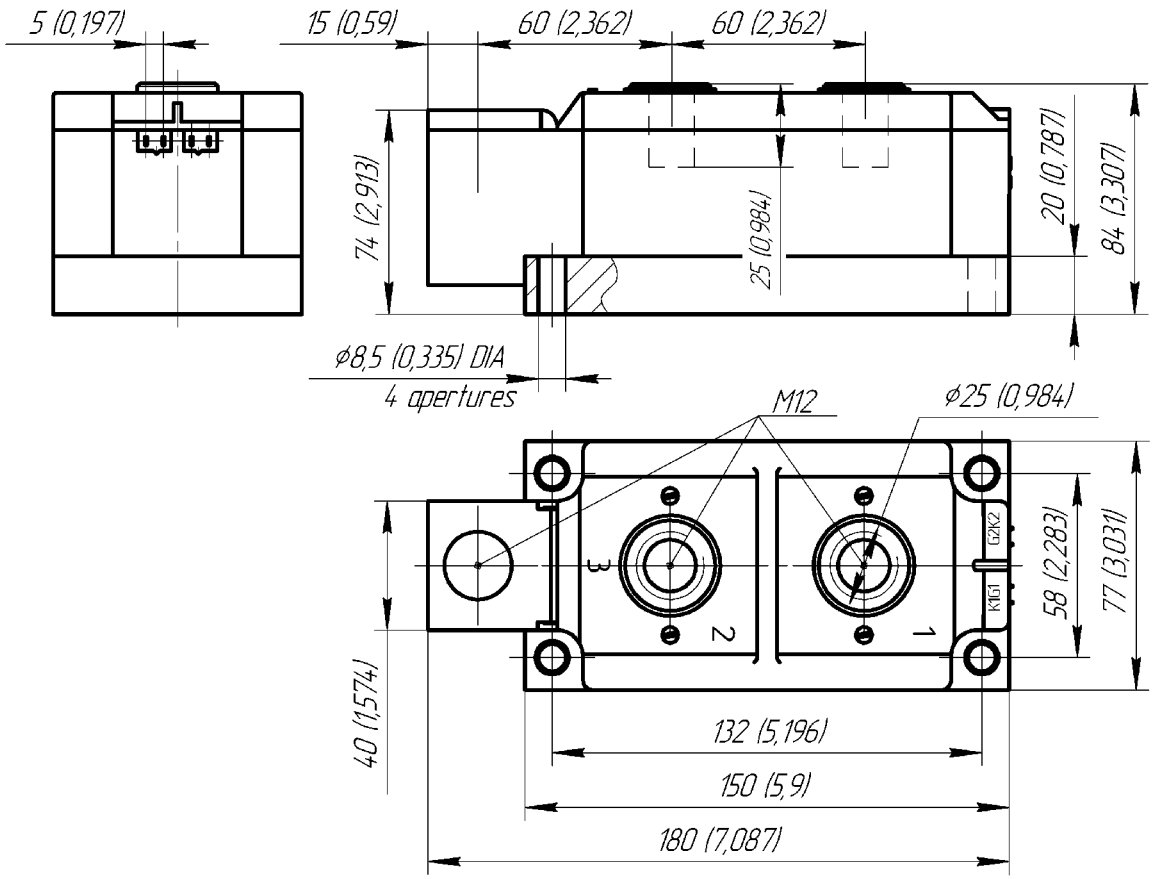
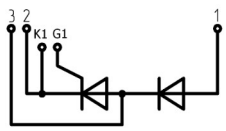
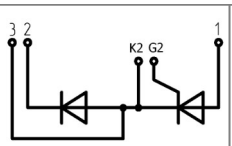


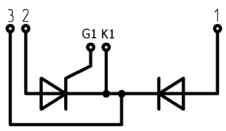




MT/D3



MD/T3



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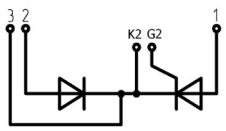

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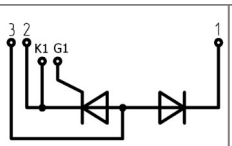
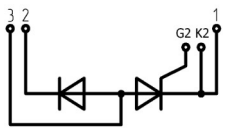


MT/D5



MD/T5

All dimensions in millimeters (inches)

MAXIMUM ALLOWABLE RATINGS

Symbols and parameters		Units	Values	Test conditions	
ON-STATE					
I_{TAV}	Maximum allowable mean on-state current	A	400 418	T_c=87 °C; T_c=85 °C; 180° half-sine wave; 50 Hz	
I_{TRMS}	RMS on-state current	A	628	T_c=87 °C; 180° half-sine wave; 50 Hz	
I_{TSM}	Surge on-state current	kA	16.0 18.0	T_j=$T_{j\,max}$ T_j=25 °C	180° half-sine wave; t_p=10 ms; single pulse; V_D=V_R=0 V; Gate pulse: I_G=2 A; t_{GP}=50 μs; di_G/dt≥1 A/μs
			17.0 20.0	T_j=$T_{j\,max}$ T_j=25 °C	180° half-sine wave; t_p=8.3 ms; single pulse; V_D=V_R=0 V; Gate pulse: I_G=2 A; t_{GP}=50 μs; di_G/dt≥1 A/μs
I^2t	Safety factor	$A^2s{\cdot}10^3$	1200 1600	T_j=$T_{j\,max}$ T_j=25 °C	180° half-sine wave; t_p=10 ms; single pulse; V_D=V_R=0 V; Gate pulse: I_G=2 A; t_{GP}=50 μs; di_G/dt≥1 A/μs
			1100 1600	T_j=$T_{j\,max}$ T_j=25 °C	180° half-sine wave; t_p=8.3 ms; single pulse; V_D=V_R=0 V; Gate pulse: I_G=2 A; t_{GP}=50 μs; di_G/dt≥1 A/μs
BLOCKING					
V_{DRM}, V_{RRM}	Repetitive peak off-state and Repetitive peak reverse voltages	V	3800...4400	$T_{j\,min}$< T_j <$T_{j\,max}$; 180° half-sine wave; 50 Hz; Gate open	
V_{DSM}, V_{RSM}	Non-repetitive peak off-state and Non-repetitive peak reverse voltages	V	3900...4500	$T_{j\,min}$< T_j <$T_{j\,max}$; 180° half-sine wave; single pulse; Gate open	
V_D, V_R	Direct off-state and Direct reverse voltages	V	$0.6{\cdot}V_{DRM}$ $0.6{\cdot}V_{RRM}$	T_j=$T_{j\,max}$; Gate open	
TRIGGERING					
I_{FGM}	Peak forward gate current	A	8	T_j=$T_{j\,max}$	
V_{RGM}	Peak reverse gate voltage	V	5		
P_G	Gate power dissipation	W	4	T_j=$T_{j\,max}$ for DC gate current	
SWITCHING					
$(di_T/dt)_{crit}$	Critical rate of rise of on-state current non-repetitive (f=1 Hz)	A/μs	1000	T_j=$T_{j\,max}$; V_D=$0.67{\cdot}V_{DRM}$; I_{TM}=2400 A; Gate pulse: I_G=2 A; t_{GP}=50 μs; di_G/dt≥2 A/μs	
THERMAL					
T_{stg}	Storage temperature	°C	–40...+50		
T_j	Operating junction temperature	°C	–40...+125		
$T_{c\,op}$	Operating temperature	°C	–40...+125		
MECHANICAL					
a	Acceleration under vibration	m/s^2	50		

CHARACTERISTICS

Symbols and parameters		Units	Values	Conditions	
ON-STATE					
V_{TM}	Peak on-state voltage, max	V	2.60	T_j=25 °C; I_{TM}=2512 A	
$V_{T(TO)}$	On-state threshold voltage, max	V	1.277	T_j=$T_{j\,max}$; 0.5 π I_{TAV} < I_T < 1.5 π I_{TAV}	
r_T	On-state slope resistance, max	mΩ	0.619		
I_L	Latching current, max	mA	1500	T_j=25 °C; V_D=12 V; Gate pulse: I_G=2 A; t_{GP}=50 μs; di_G/dt≥1 A/μs	
I_H	Holding current, max	mA	300	T_j=25 °C; V_D=12 V; Gate open	
BLOCKING					
I_{DRM}, I_{RRM}	Repetitive peak off-state and Repetitive peak reverse currents, max	mA	150 4.00	T_j=$T_{j\,max}$ T_j= 25 °C	V_D=V_{DRM}; V_R=V_{RRM}
$(dv_D/dt)_{crit}$	Critical rate of rise of off-state voltage[1], min	V/μs	200, 320, 500, 1000, 1600, 2000, 2500	T_j=$T_{j\,max}$; V_D=0.67·V_{DRM}; Gate open	
TRIGGERING					
V_{GT}	Gate trigger direct voltage, max	V	3.00 2.50 1.50	T_j= $T_{j\,min}$ T_j=25 °C T_j= $T_{j\,max}$	V_D=12 V; I_D=3 A; Direct gate current
I_{GT}	Gate trigger direct current, max	mA	400 250 150	T_j= $T_{j\,min}$ T_j= 25 °C T_j= $T_{j\,max}$	
V_{GD}	Gate non-trigger direct voltage, min	V	0.35	T_j=$T_{j\,max}$; V_D=0.67·V_{DRM}; Direct gate current	
I_{GD}	Gate non-trigger direct current, min	mA	40.00		
SWITCHING					
t_{gd}	Delay time, max	μs	2.75	T_j=25 °C; V_D=1500 V; I_{TM}=I_{TAV}; di/dt=200 A/μs; Gate pulse: I_G=2 A; V_G=20 V; t_{GP}=50 μs; di_G/dt=2 A/μs	
t_{gt}	Turn-on time, max	μs	16.0		
t_q	Turn-off time[2], max	μs	500	dv_D/dt=50 V/μs; T_j=$T_{j\,max}$; I_{TM}= I_{TAV}; di_R/dt=-10 A/μs; V_R=100V; V_D=0.67 V_{DRM};	
Q_{rr}	Recovered charge, max	μC	2970	T_j=$T_{j\,max}$; I_{TM}=I_{TAV}; di_R/dt=-5 A/μs; V_R=100 V;	
t_{rr}	Reverse recovery time, max	μs	53.0		
I_{rr}	Reverse recovery current, max	A	112		
THERMAL					
R_{thjc}	Thermal resistance, junction to case			180° half-sine wave, 50 Hz	
	per module	°C/W	0.0250		
	per arm	°C/W	0.0500		
R_{thch}	Thermal resistance, case to heatsink				
	per module	°C/W	0.0080		
	per arm	°C/W	0.0160		
INSULATION					
V_{ISOL}	Insulation test voltage	kV	3.00	Sine wave, 50 Hz; RMS	t=60 sec
			3.60		t=1 sec
MECHANICAL					
M_1	Mounting torque (M8)[1]	Nm	9.00	Tolerance ± 15%	
M_2	Terminal connection torque (M12)[1]	Nm	18.00	Tolerance ± 15%	
m	Weight, max	g	4100		

PART NUMBERING GUIDE

MT	3	-	400	-	44	-	A2	E2	-	D	-	N
1	2		3		4		5	6		7		8

1. Thyristor module (MT)
   Thyristor – Diode module (MT/D)
   Diode – Thyristor module (MD/T)
2. Circuit Schematic:
   3 – serial connection
   4 – common Cathode
   5 – common Anode
3. Average On-state Current, A
4. Voltage Code
5. Critical rate of rise of off-state voltage
6. Group of turn-off time (dv_D/dt=50 V/μs)
7. Package Type (M.D)
8. Ambient Conditions:
   N – Normal

NOTES

[1] Critical rate of rise of off-state voltage

Symbol of Group	P2	K2	E2	A2	T1	P1	M1
$(dv_D/dt)_{crit}$, V/μs	200	320	500	1000	1600	2000	2500

[2] Turn-off time (dv_D/dt=50 V/μs)

Symbol of group	E2
t_q, μs	500

[3] The screws must be lubricated

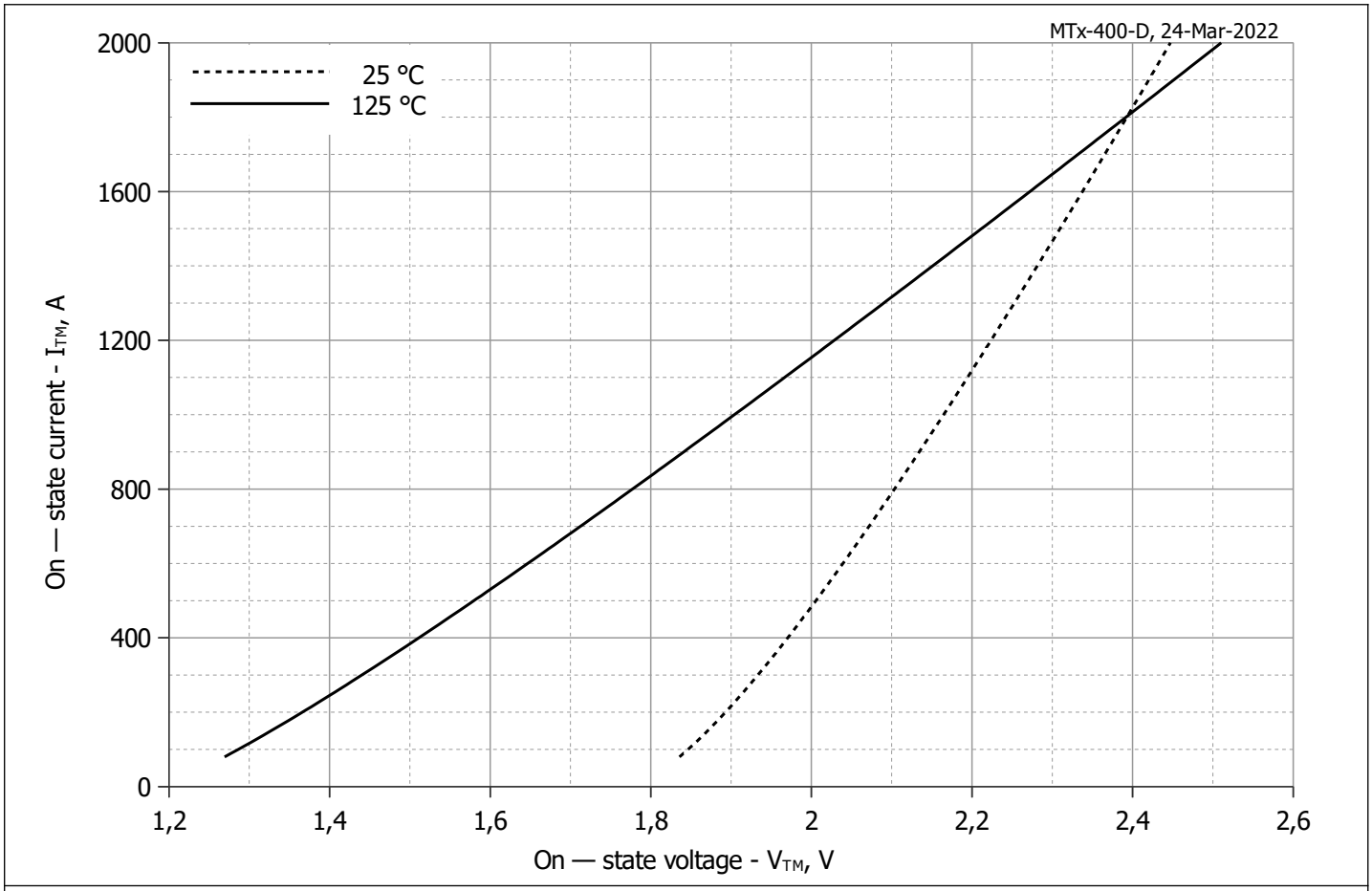


Fig 1 – On-state characteristics of Limit device

Analytical function for On-state characteristic:

$$V_T = A + B \cdot i_T + C \cdot \ln(i_T + 1) + D \cdot \sqrt{i_T}$$

	Coefficients for max curves	
	T_j = 25°C	$T_j = T_{j\,max}$
A	1.76440369	1.19849286
B	0.00019611	0.00049189
C	-0.00086961	-0.01192254
D	0.00664511	0.00936404

On-state characteristic model (see Fig. 1)

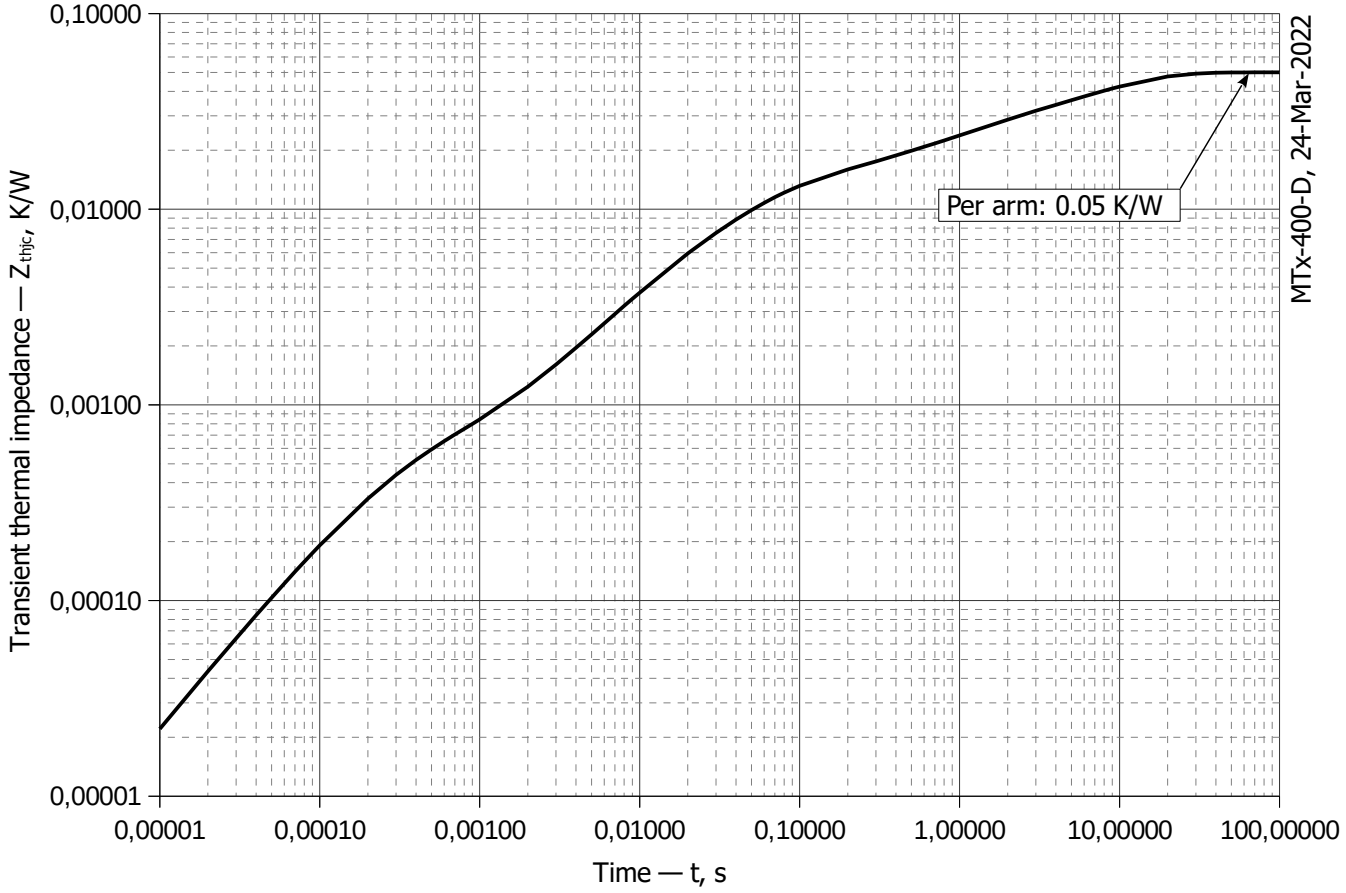


Fig 2 – Transient thermal impedance Z_{thjc} vs. time t

Analytical function for Transient thermal impedance junction to case Z_{thjc} for DC:

$$Z_{thjc} = \sum_{i=1}^{n} R_i \left(1 - e^{-\frac{t}{\tau_i}}\right)$$

Where ***i*** = 1 to ***n***, ***n*** is the number of terms in the series.

t = Duration of heating pulse in seconds.

$\mathbf{Z_{thjc}}$ = Thermal resistance at time t.

$\mathbf{R_i}$ = Amplitude of p_{th} term.

τ_i = Time constatnt of r_{th} term.

i	1	2	3	4	5	6
$\mathbf{R_i}$, **K/W**	0.02506	0.009643	0.00348	0.009712	0.001719	0.0004399
τ_i, **s**	8.474	1.11	0.2289	0.04529	0.009524	0.0002414

Transient thermal impedance junction to case Z_{thjc} model (see Fig. 2)

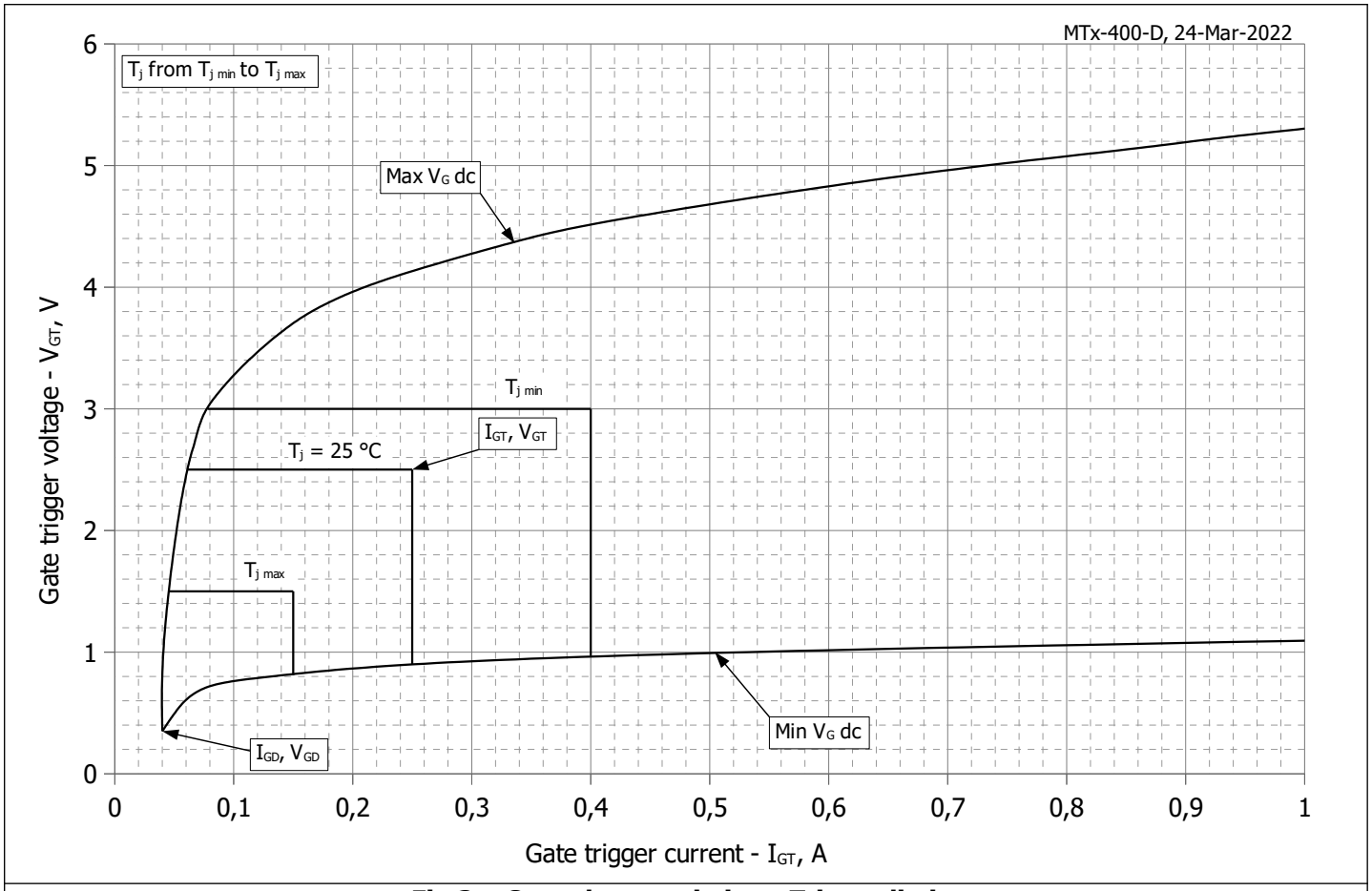


Fig 3 – Gate characteristics – Trigger limits

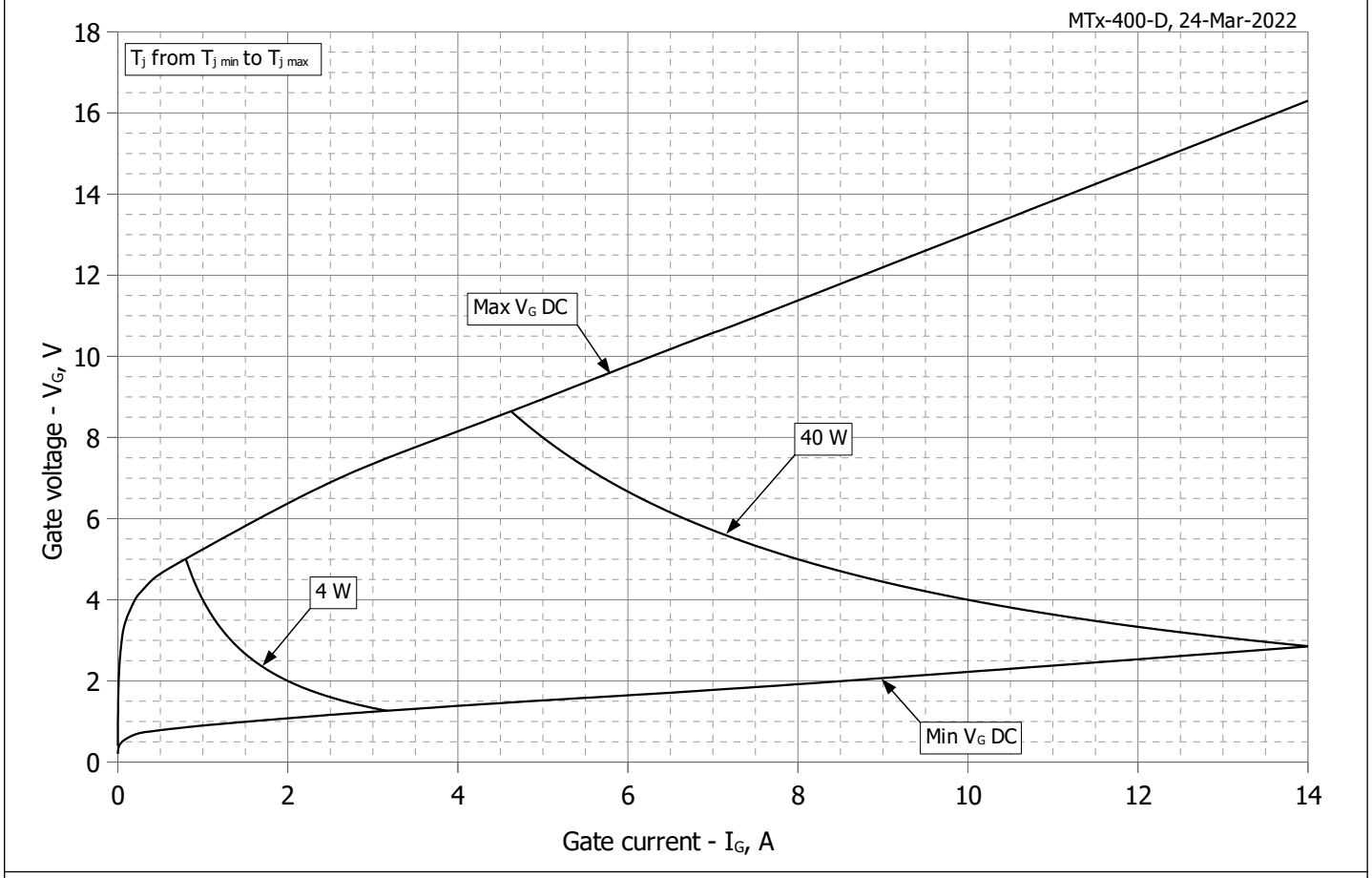


Fig 4 - Gate characteristics – Power curves

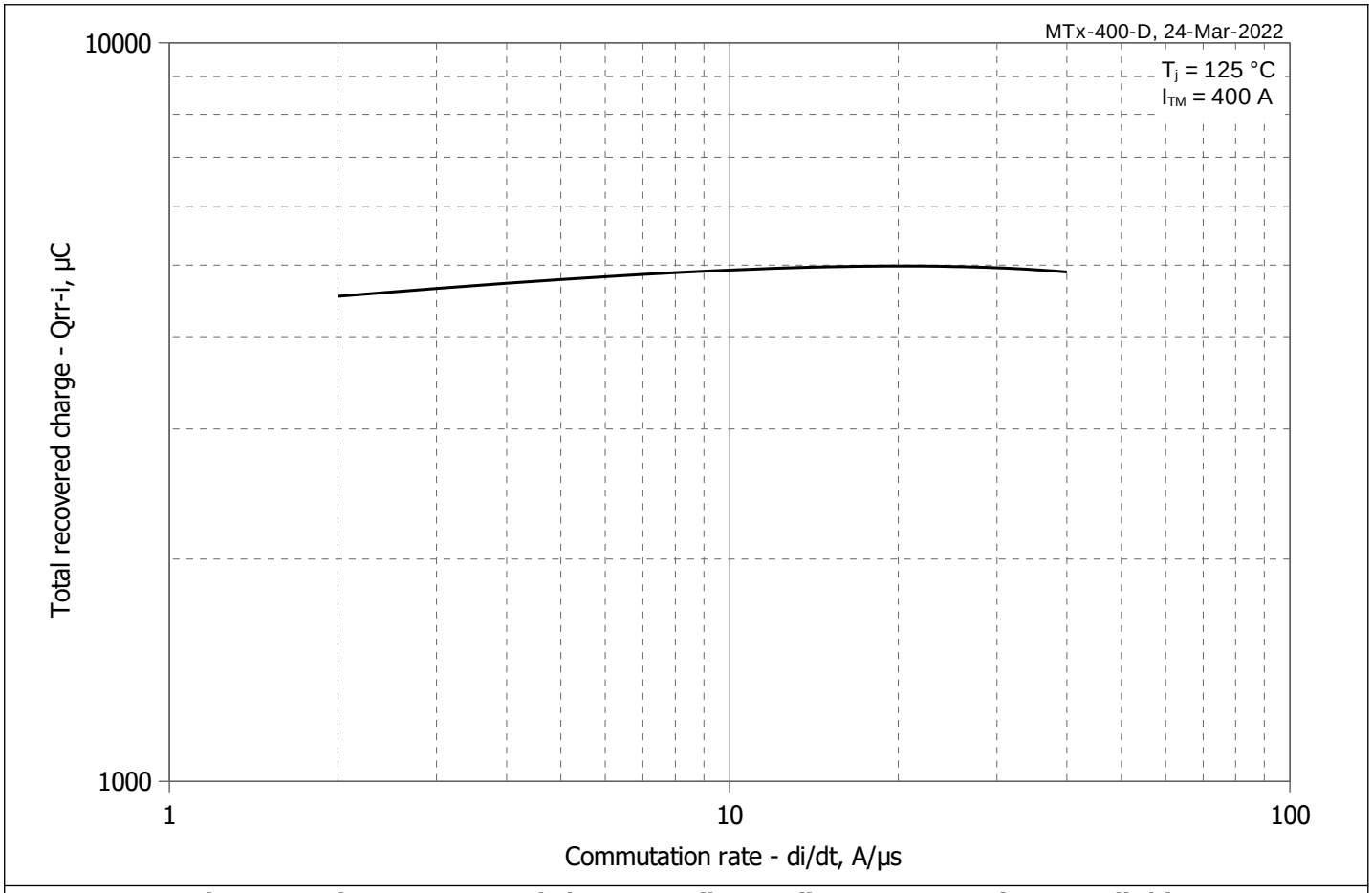


Fig 5 – Maximum recovered charge Q_{rr-i} (integral) vs. commutation rate di_R/dt

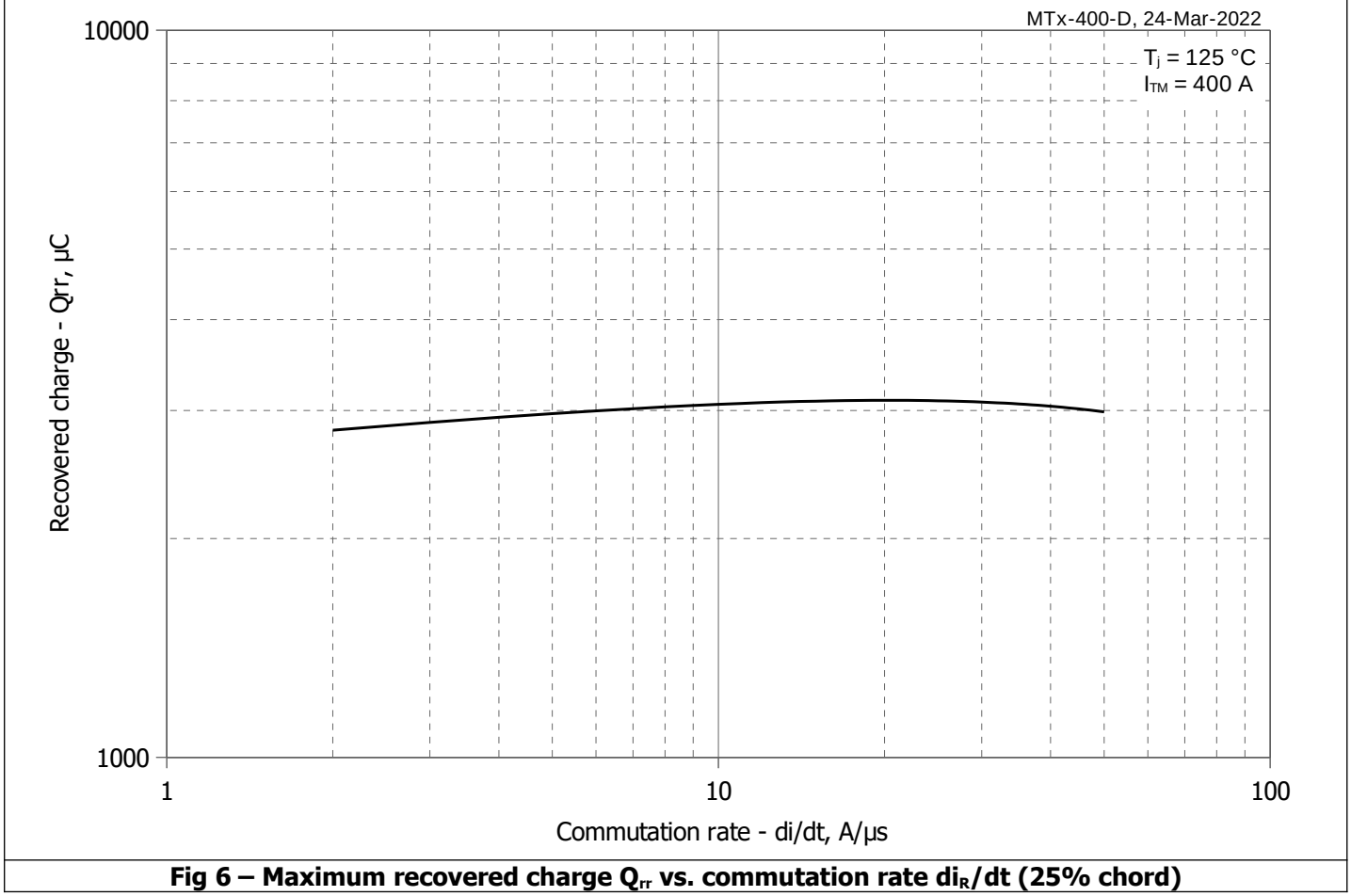


Fig 6 – Maximum recovered charge Q_{rr} vs. commutation rate di_R/dt (25% chord)

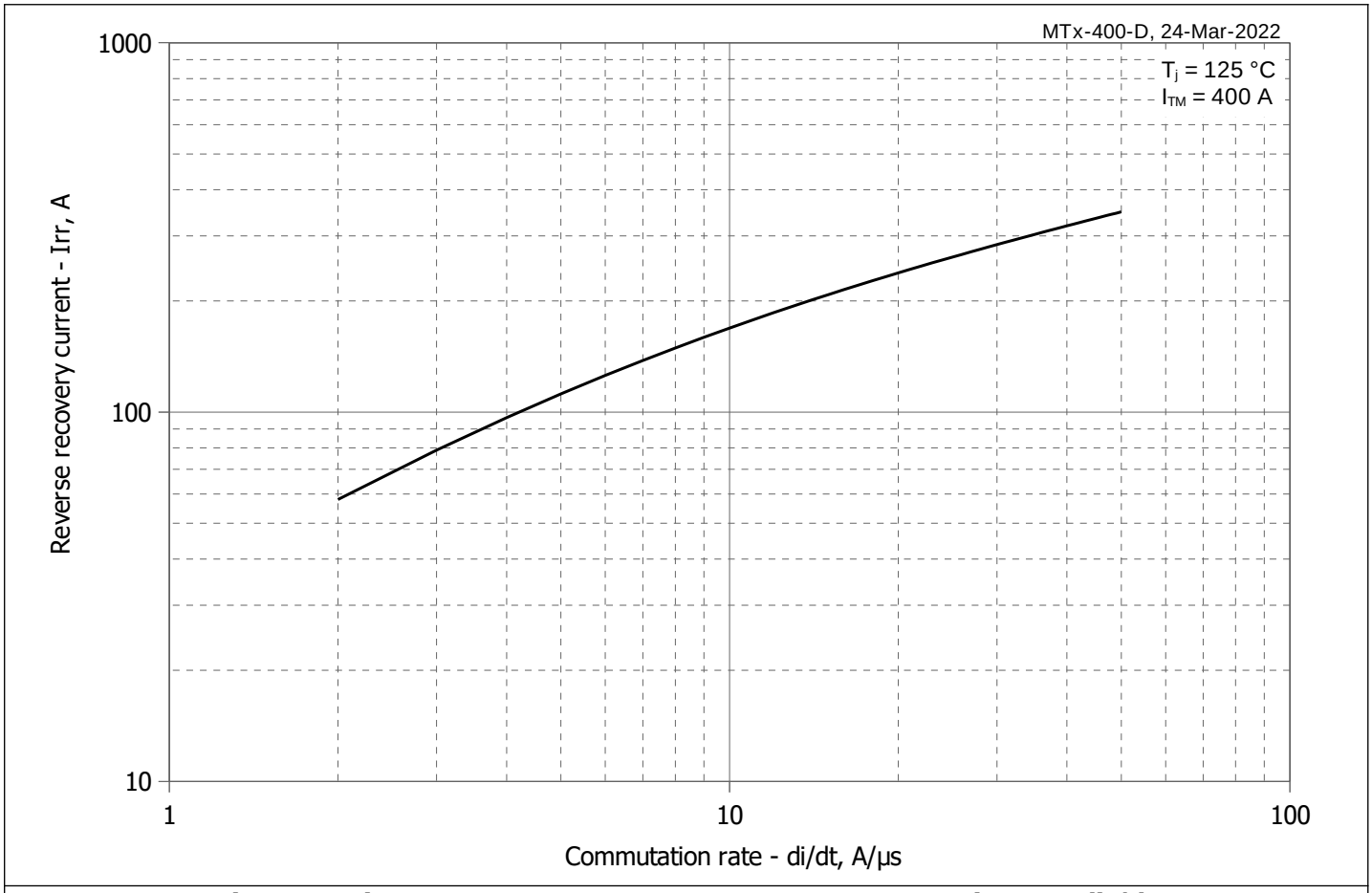


Fig 7 – Maximum reverse recovery current I_{rr} vs. commutation rate di_R/dt

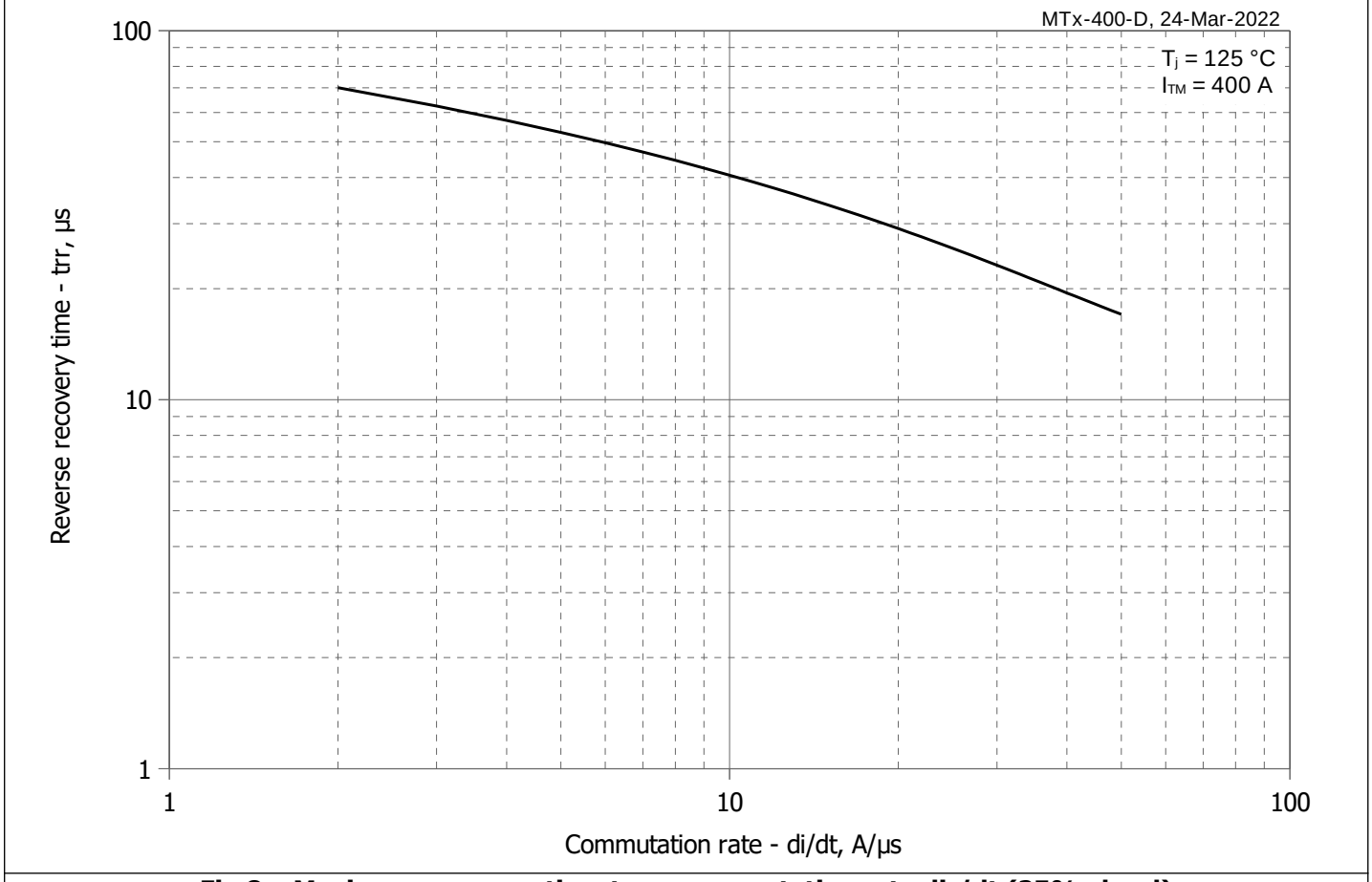


Fig 8 – Maximum recovery time t_{rr} vs. commutation rate di_R/dt (25% chord)

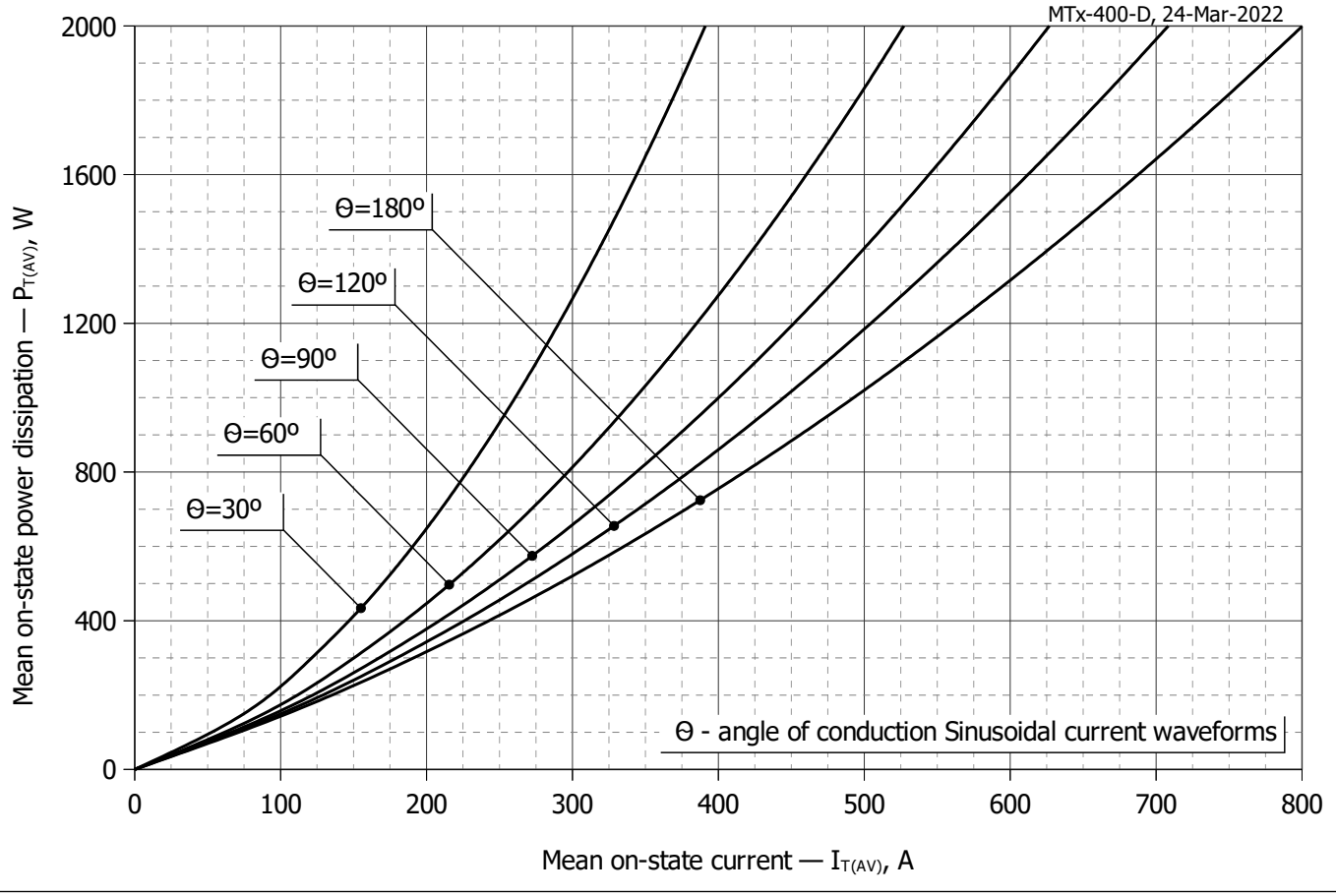


Fig. 9 - Mean on-state power dissipation P_{TAV} vs. mean on-state current I_{TAV} for sinusoidal current waveforms at different conduction angles (f=50Hz)

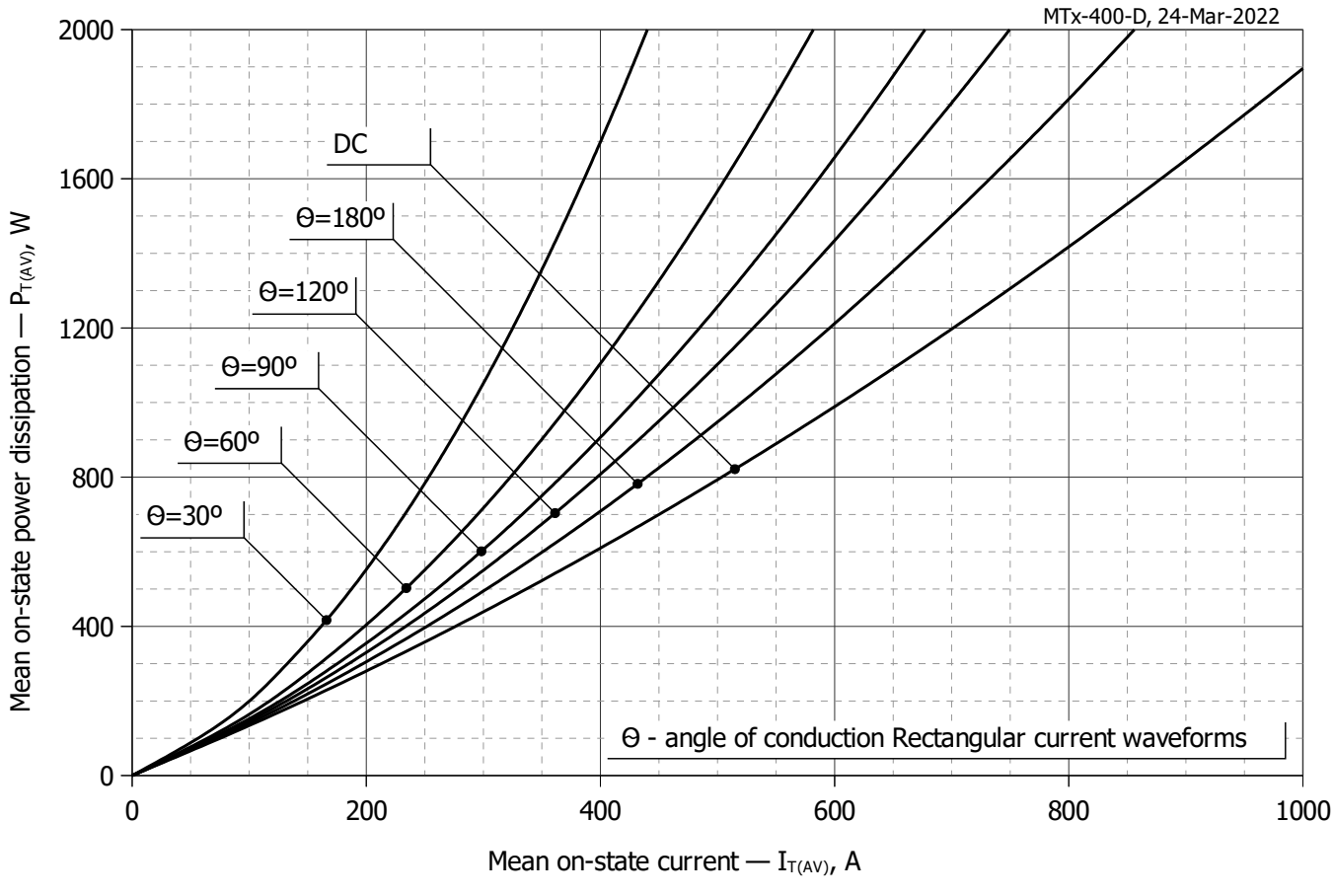


Fig. 10 – Mean on-state power dissipation P_{TAV} vs. mean on-state current I_{TAV} for rectangular current waveforms at different conduction angles and for DC (f=50Hz)

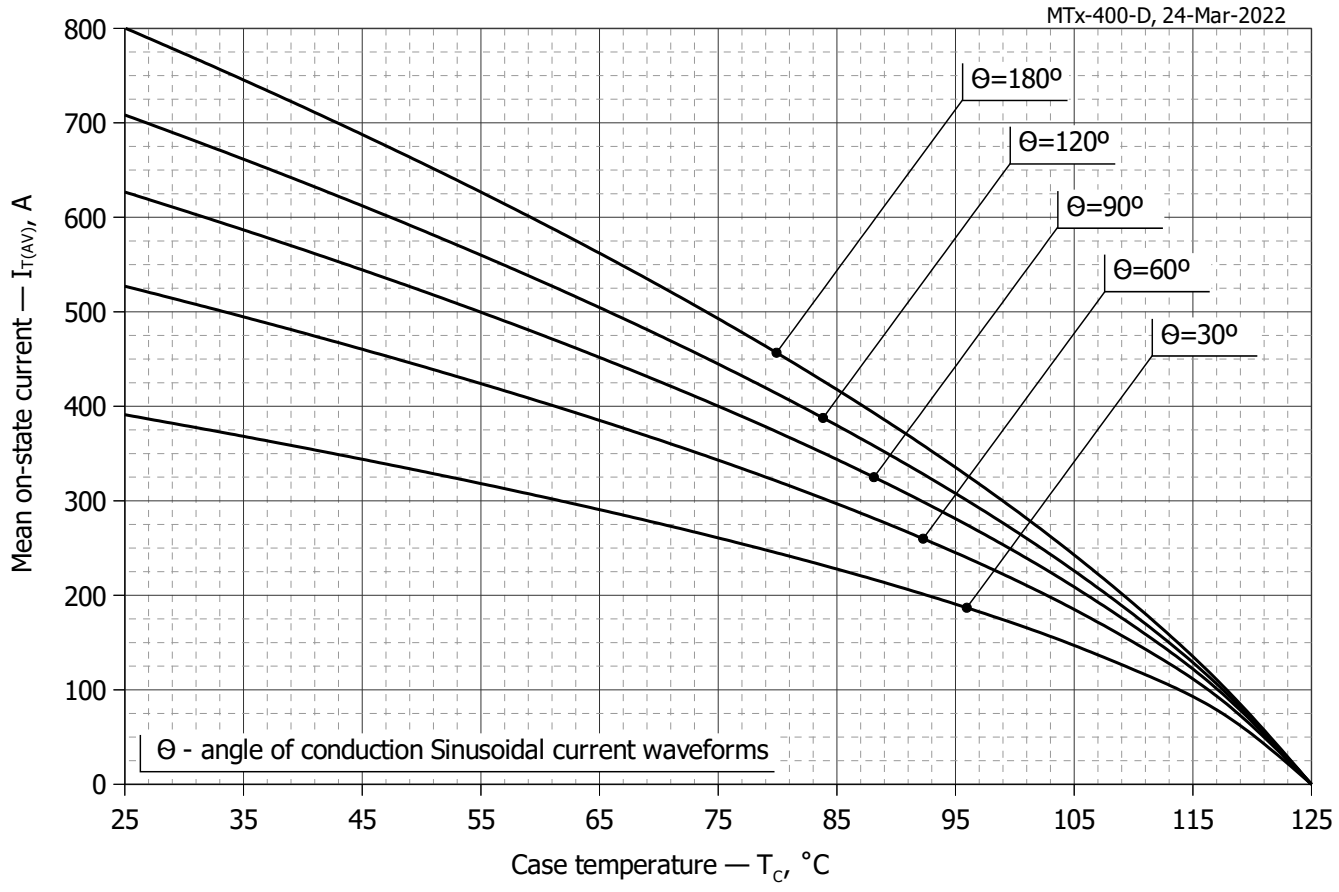


Fig. 11 – Mean on-state current I_{TAV} vs. case temperature T_C for sinusoidal current waveforms at different conduction angles (f=50Hz)

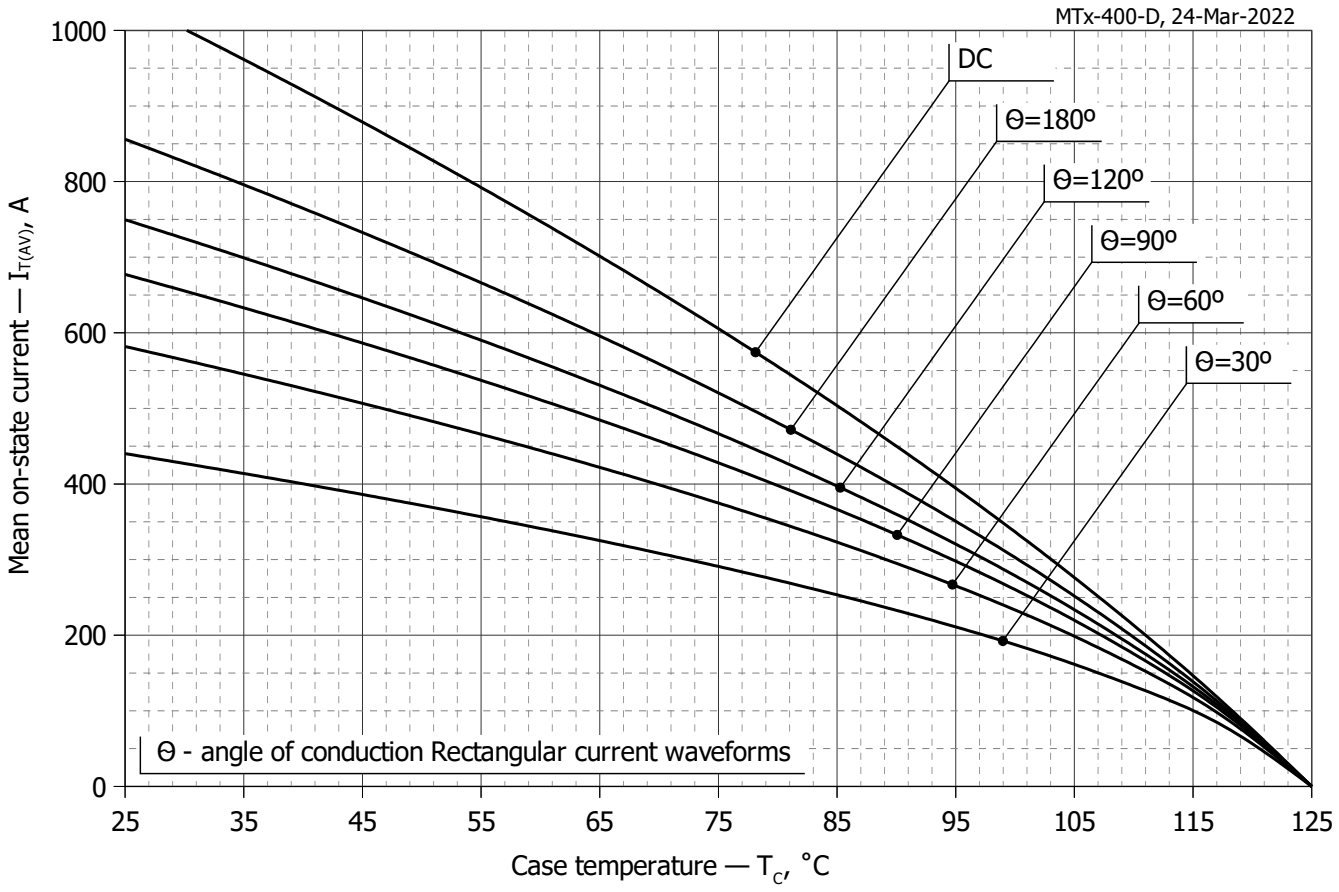


Fig. 12 - Mean on-state current I_{TAV} vs. case temperature T_C for rectangular current waveforms at different conduction angles and for DC (f=50Hz)

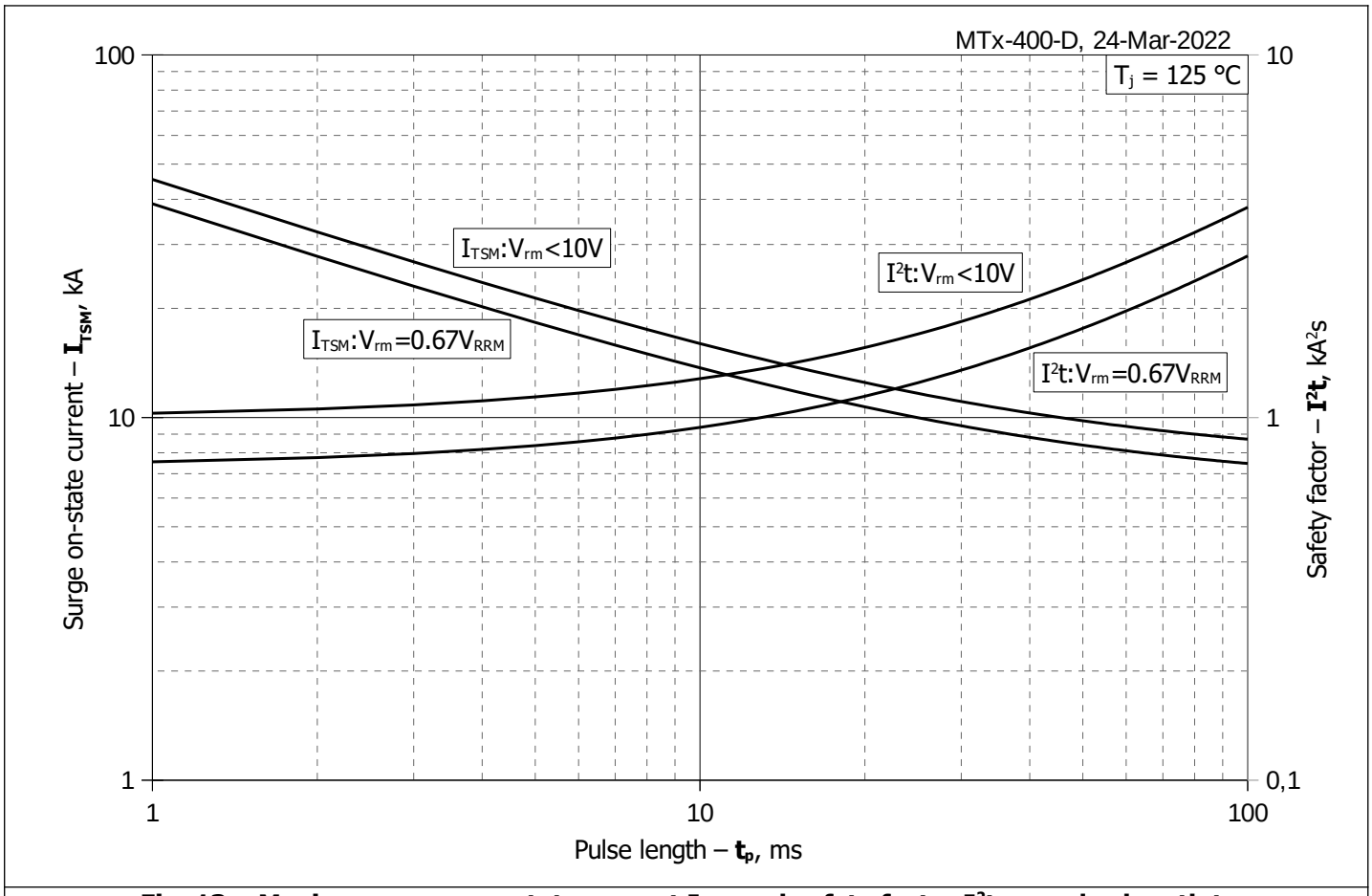


Fig. 13 – Maximum surge on-state current I_{TSM} and safety factor I^2t vs. pulse length t_p

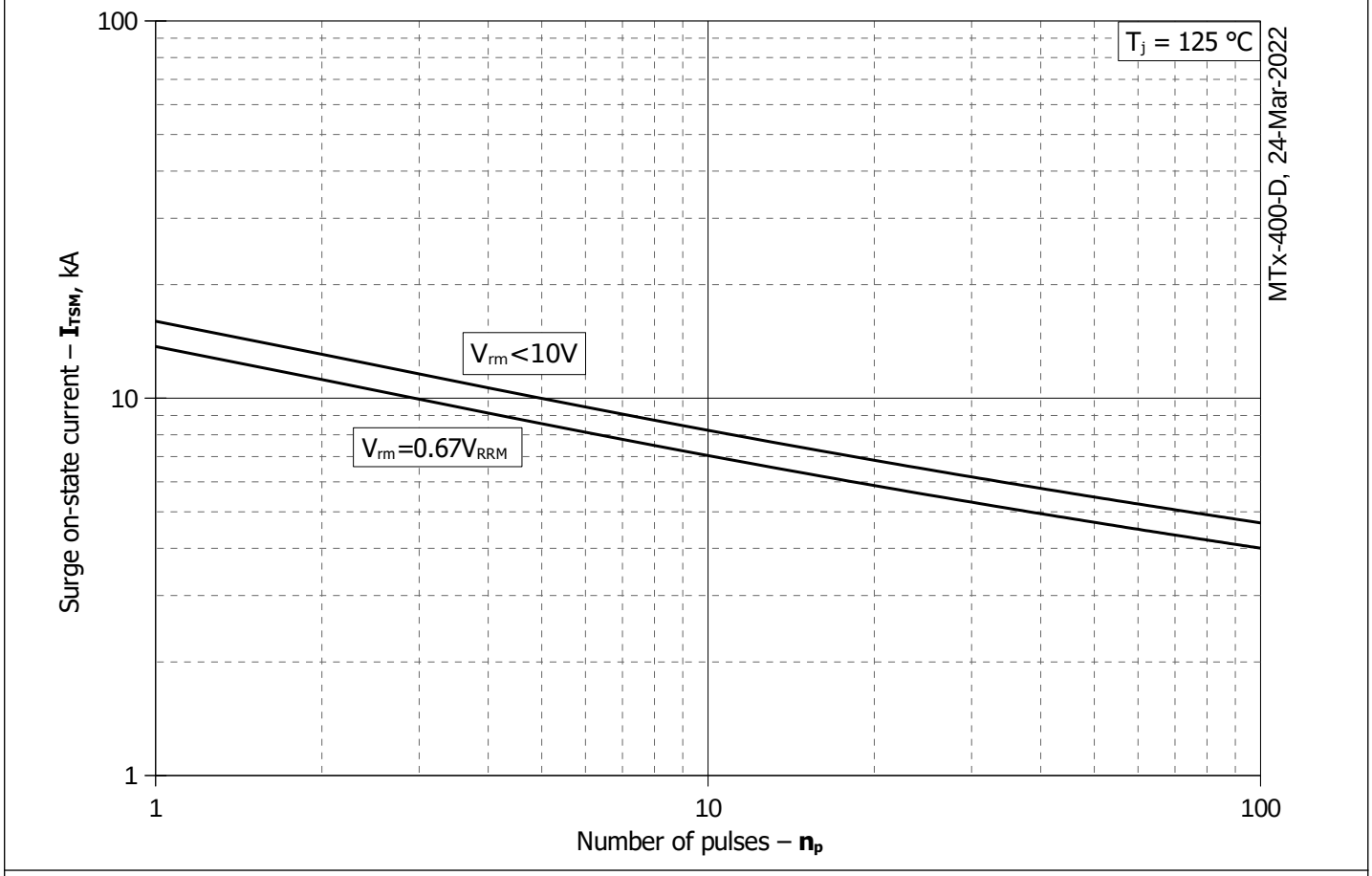


Fig. 14 - Maximum surge on-state current I_{TSM} vs. number of pulses n_p